


Search Notes 	Application/Control No. 10564454	Applicant(s)/Patent Under Reexamination SOENKSEN ET AL.
	Examiner SHEELA C CHAWAN	Art Unit 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	149, 145, 224, 159, 144	1/3/09	SCC
719	310, 315,	"	"
715	744, 835, 837, 764, 841, 210, 839, 762, 809, 804, 973, 708, 250, 866	"	"
714	E11.21	"	"
700	110, 121, 103,	"	"
702	82, 83, 35, 81	"	"
438	14, 16, 17, 18	"	"
364	552, 468.7	"	"
148	33	"	"
365	552	"	"
710	110, 121, 103	"	"
348	125, 86, 87	"	"
356	237.1, 237.2, 237.3, 237.4, 237.5	"	"
250	559.01	"	"
717	109, 113, 108	"	"
382	145, 149	7/2/09	SCC
356	237.1	7/2/09	SCC
715	835, 837	7/2/09	SCC
ABOVE SEARCH UP- DATE.		7/2/09	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY	1/3/09	SCC
INVENTORY NAME SEARCH.	"	"
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	7/2/09	SCC
382/149, 145, 224, 159, 100, 141, 155, 181.CCLS. US-PATENT TEXT SEARCH ONLY.	7/2/09	SCC
715/774, 835, 837, 764, 841, 210, 839, 762, 809, 804, 973, 250, 866, 708.CCLS. " "	7/2/09	SCC
356/237.1, 237.2.CCLS. " "	7/2/09	SCC

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SEARCH NOTES		
Search Notes	Date	Examiner
INTERFERENCE SEARCH .	7/2/09	SCC
SEARCH IEEE OR INSPECT DATA BASE.	7/2/09	SCC
SEARCH UP-DATE.	7/2/09	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	145, 149	7/2/09	SCC
356	237.1	7/2/09	SCC
715	835 , 837	7/2/09	SCC